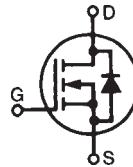


HiPerFET™
Power MOSFET
Q2-Class

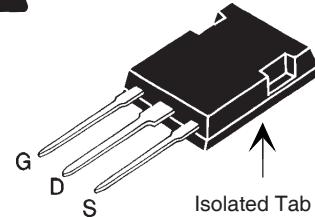
IXFR66N50Q2

N-Channel Enhancement Mode
Avalanche Rated, High dv/dt, Low Q_g
Low intrinsic R_g, low t_{rr}



V_{DSS} = 500V
I_{D25} = 50A
R_{DS(on)} ≤ 85mΩ
t_{rr} ≤ 250ns

ISOPLUS247 (IXFR)



G = Gate D = Drain
S = Source

Symbol	Test Conditions	Maximum Ratings	
V _{DSS}	T _J = 25°C to 150°C	500	V
V _{DGR}	T _J = 25°C to 150°C, R _{GS} = 1MΩ	500	V
V _{GSS}	Continuous	± 30	V
V _{GSM}	Transient	± 40	V
I _{D25}	T _C = 25°C	50	A
I _{DM}	T _C = 25°C, pulse width limited by T _{JM}	264	A
I _A	T _C = 25°C	66	A
E _{AS}	T _C = 25°C	4	J
dV/dt	I _S ≤ I _{DM} , V _{DD} ≤ V _{DSS} , T _J ≤ 150°C	20	V/ns
P _D	T _C = 25°C	500	W
T _J		-55 ... +150	°C
T _{JM}		150	°C
T _{stg}		-55 ... +150	°C
T _L	Maximum lead temperature for soldering	300	°C
T _{SOLD}	Plastic body for 10s	260	°C
V _{ISOL}	50/60 Hz, RMS, 1 minute	2500	V~
F _c	Mounting force	20..120/4.5..27	N/lb.
Weight		5	g

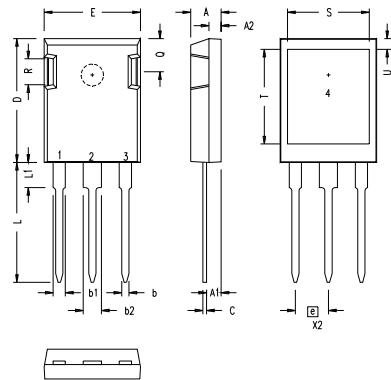
Symbol	Test Conditions (T _J = 25°C, unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
BV _{DSS}	V _{GS} = 0V, I _D = 3mA	500		V
V _{GS(th)}	V _{DS} = V _{GS} , I _D = 8mA	3.0		V
I _{GSS}	V _{GS} = ± 30V, V _{DS} = 0V			± 200 nA
I _{DSS}	V _{DS} = V _{DSS} V _{GS} = 0V			50 μA 2 mA
R _{DS(on)}	V _{GS} = 10V, I _D = 33A, Note 1			85 mΩ

Symbol	Test Conditions (T _J = 25°C unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
g_{fs}	V _{DS} = 10V, I _D = 33A, Note 1	30	44	S
C_{iss}	V _{GS} = 0V, V _{DS} = 25V, f = 1MHz	9125	pF	
C_{oss}		1200	pF	
C_{rss}		318	pF	
t_{d(on)}	Resistive Switching Times V _{GS} = 10V, V _{DS} = 0.5 • V _{DSS} , I _D = 33A R _G = 1Ω (External)	32	ns	
t_r		16	ns	
t_{d(off)}		60	ns	
t_f		10	ns	
Q_{g(on)}	V _{GS} = 10V, V _{DS} = 0.5 • V _{DSS} , I _D = 33A	200	nC	
Q_{gs}		47	nC	
Q_{gd}		98	nC	
R_{thJC}		0.25 °C/W		
R_{thCS}			0.15	°C/W

Source-Drain Diode		Characteristic Values		
	T _J = 25°C unless otherwise specified)	Min.	Typ.	Max.
I_s	V _{GS} = 0V			66 A
I_{SM}	Repetitive, pulse width limited by T _{JM}			264 A
V_{SD}	I _F = I _S , V _{GS} = 0V, Note 1			1.5 V
t_{rr}	I _F = 25A, -di/dt = 100A/μs V _R = 100V, V _{GS} = 0V	1	250 ns	
Q_{RM}			μC	
I_{RM}		10	A	

Note 1: Pulse test, t ≤ 300μs; duty cycle, d ≤ 2%.

ISOPLUS247 (IXFR) Outline



SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.190	.205	4.83	5.21
A1	.090	.100	2.29	2.54
A2	.075	.085	1.91	2.16
b	.045	.055	1.14	1.40
b1	.075	.084	1.91	2.13
b2	.115	.123	2.92	3.12
C	.024	.031	0.61	0.80
D	.819	.840	20.80	21.34
E	.620	.635	15.75	16.13
e	.215 BSC		5.45 BSC	
L	.780	.800	19.81	20.32
L1	.150	.170	3.81	4.32
Q	.220	.244	5.59	6.20
R	.170	.190	4.32	4.83
S	.520	.540	13.21	13.72
T	.620	.640	15.75	16.26
U	.065	.080	1.65	2.03

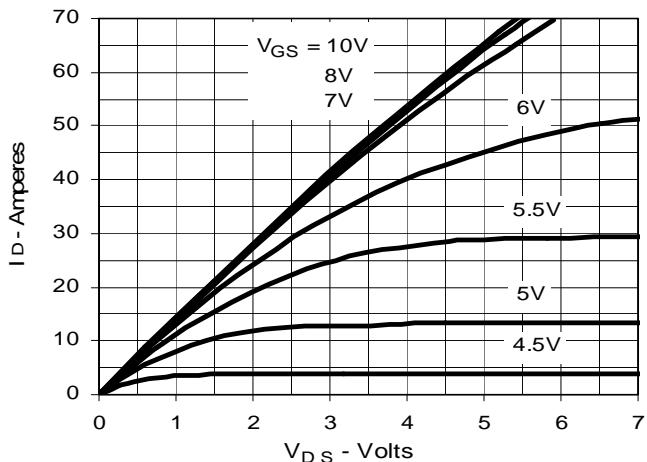
1 – GATE
2 – DRAIN (COLLECTOR)
3 – SOURCE (EMITTER)
4 – NO CONNECTION

NOTE: This drawing will meet all dimensions requirement of JEDEC outline TO-247AD except screw hole.

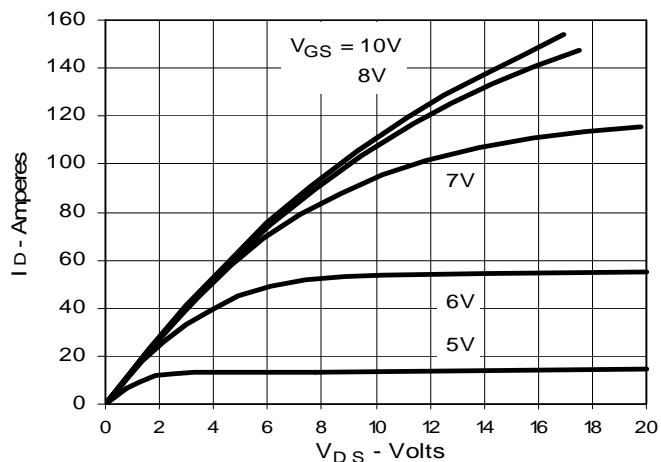
IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents: 4,835,592 4,931,844 5,049,961 5,237,481 6,162,665 6,404,065 B1 6,683,344 6,727,585 7,005,734 B2 7,157,338B2 4,850,072 5,017,508 5,063,307 5,381,025 6,259,123 B1 6,534,343 6,710,405 B2 6,759,692 7,063,975 B2 4,881,106 5,034,796 5,187,117 5,486,715 6,306,728 B1 6,583,505 6,710,463 6,771,478 B2 7,071,537

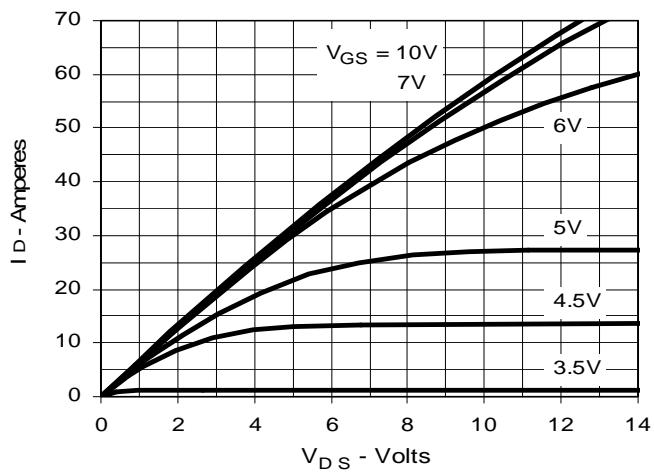
**Fig. 1. Output Characteristics
@ 25°C**



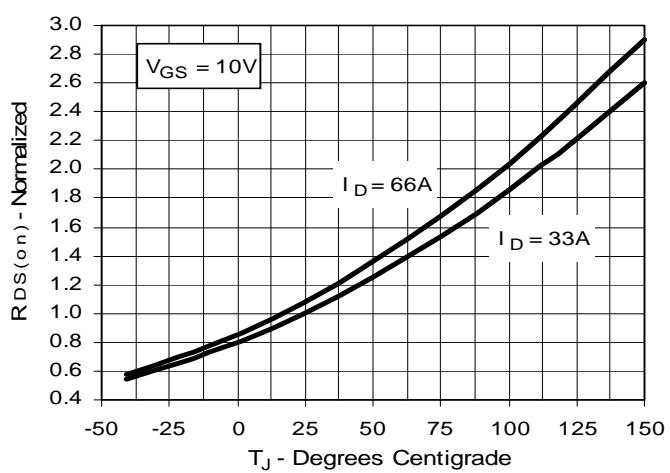
**Fig. 2. Extended Output Characteristics
@ 25°C**



**Fig. 3. Output Characteristics
@ 125°C**



**Fig. 4. $R_{DS(on)}$ Normalized to 0.5 I_{D25} Value
vs. Junction Temperature**



**Fig. 5. $R_{DS(on)}$ Normalized to 0.5 I_{D25} Value
vs. I_D**

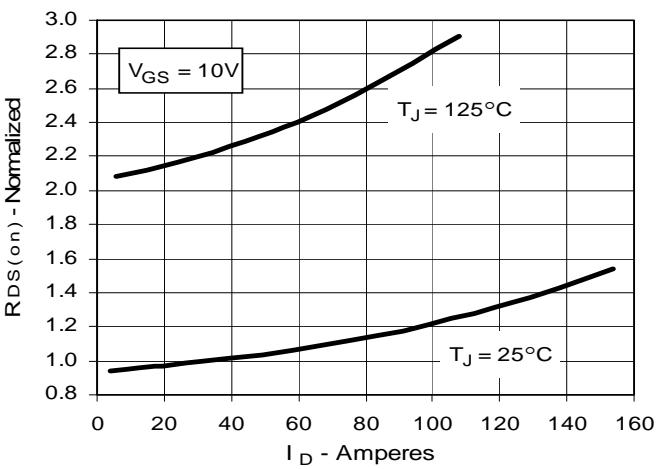


Fig. 6. Drain Current vs. Case Temperature

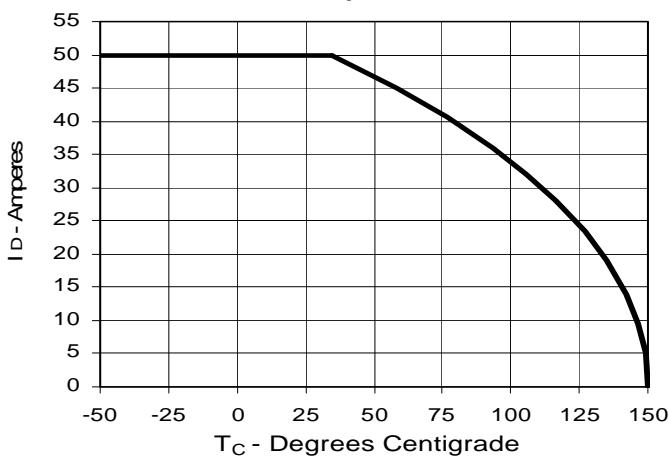
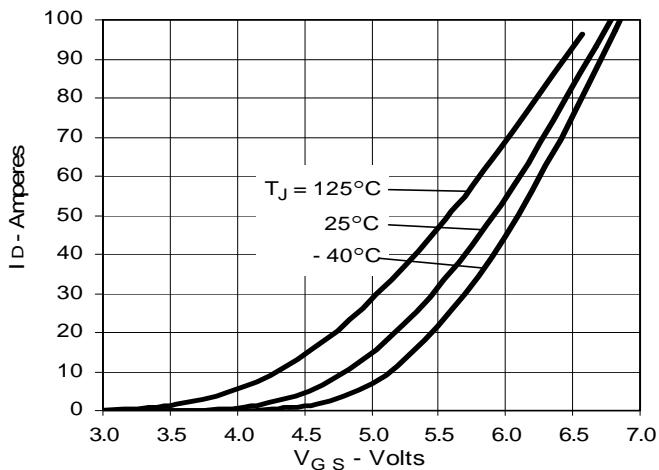
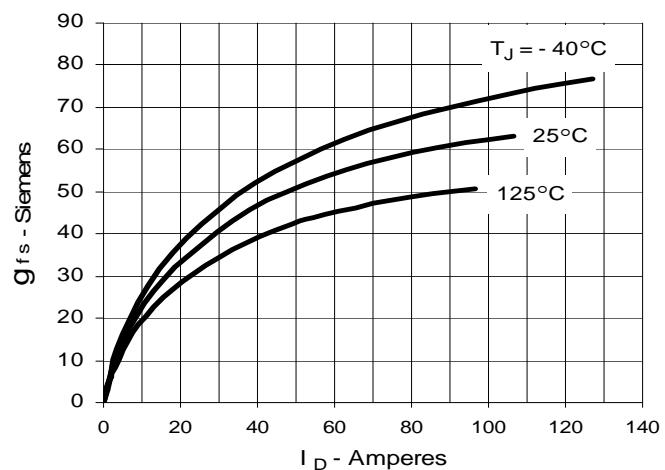
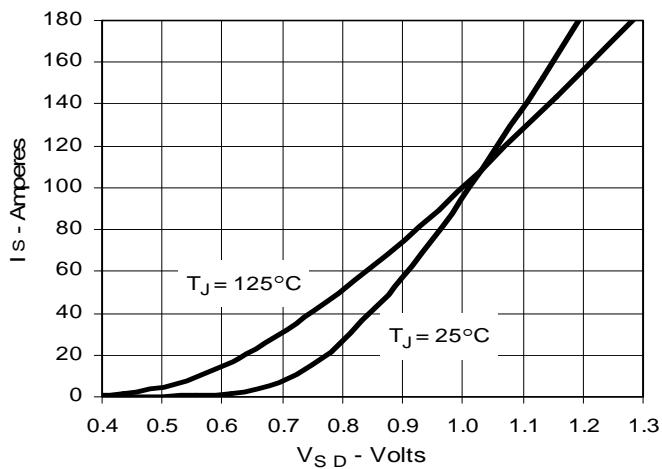
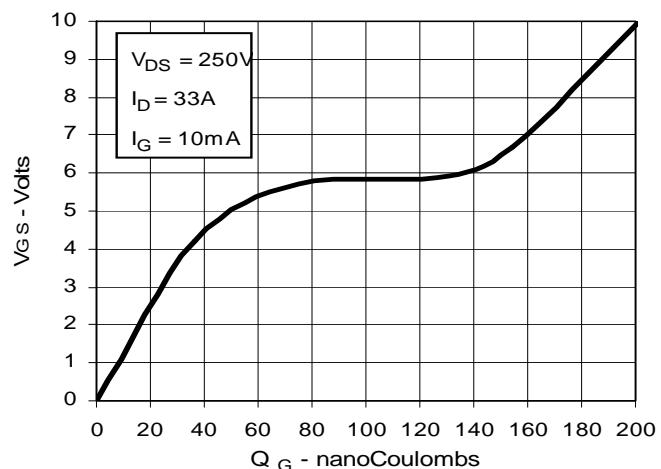
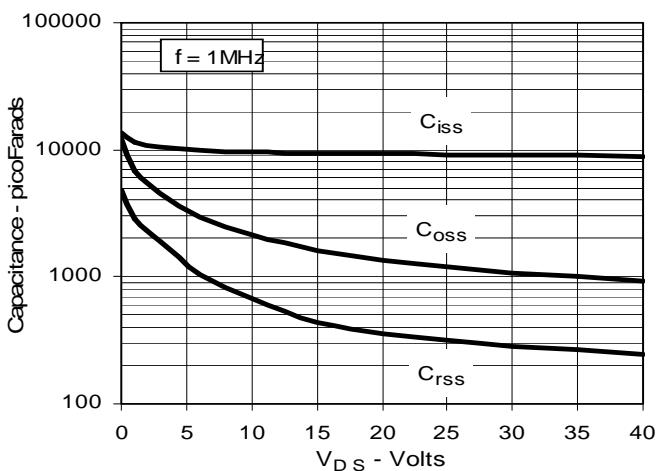


Fig. 7. Input Admittance**Fig. 8. Transconductance****Fig. 9. Source Current vs. Source-To-Drain Voltage****Fig. 10. Gate Charge****Fig. 11. Capacitance****Fig. 12. Maximum Transient Thermal Impedance**